

DETAILED ACTION**EXAMINER'S AMENDMENT**

1. An examiner's amendment to the record appears below. Should the changes and/or additions be unacceptable to applicant, an amendment may be filed as provided by 37 CFR 1.312. To ensure consideration of such an amendment, it **MUST** be submitted no later than the payment of the issue fee.

Authorization for this examiner's amendment was given in a telephone interview with Enoch E. Peavey on November 24, 2008.

The application has been amended as follows:

In the Specification:

In paragraph ⁸009, line 24, the words "(see claim 1)" have been deleted

In paragraph 0013, line 4, the words "(see claim 2)" have been deleted

In paragraph 0014, line ⁵4, the words "(see claim 3)" have been deleted

In paragraph 0015, line 3, the words "(see claim 4)" have been deleted

In paragraph 0016, lines 5-6, the words "(see claim 5)" have been deleted

In paragraph 0017, line 6, the words "(see claim 6)" have been deleted

In paragraph 0018, line 6, the words "(see claim 7)" have been deleted

In paragraph 0019, lines 5-6, the words "(see claim 8)" have been deleted

In paragraph 0020, line 5, the words "(see claim 9)" have been deleted

In paragraph 0020, line 10, the words "(see claim 10)" have been deleted

In paragraph 0020, line 15, the words "(see claim 11)" have been deleted

In paragraph 0021, line 16, the words "(see claim 12)" have been deleted

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In paragraph 0026, line ⁴10, the words "(see claim 13)" have been deleted

In paragraph 0027, lines 4-5, the words "(see claim 14)" have been deleted

In paragraph 0027, lines 13-14, the words "(see claim 15)" have been deleted

In paragraph 0027, lines 16-17, the words "(see claim 16)" have been deleted

In paragraph 0028, line 20, the words "(see claim 17)" have been deleted

Allowable Subject Matter

2. **Claims 1-6, 10-11 and 15-16** are allowed.
3. The following is an examiner's statement of reasons for allowance:

In terms of claim 1, the prior art of record does not teach alone or in combination a image sensor test system comprising a contact arm configured to pick up and move the inverted image sensor inverted by the first inverter, the contact arm being configured to bring input/output terminals of the inverted image sensor into electrical contact with a contact of the test head; an attachment portion configured to attach the light source and the test head to the image sensor test system so as to place the light source and the test head beneath the image sensor, in combination with all other elements in claim 1.

As to claims 2-5, the claims are allowed as they further limit allowed claim 1.

In terms of claim 6, the prior art of record does not teach alone or in combination a image sensor test system wherein each of the first and second inverters comprises a rotation mechanism, wherein the rotation mechanism comprises a pinion

